

#### HAC RF EMISSIONS TEST REPORT

### FCC 47 CFR § 20.19 ANSI C63.19-2011

For

GSM/WCDMA/LTE Phone + BT/BLE, DTS/UNII a/b/g/n/ac/ax, WPT and NFC

MODEL NUMBER: SM-G780G/DSM, SM-G780G/DS, SM-G780G

FCC ID: A3LSMG780G1

REPORT NUMBER: 4790047196-S2V1

**ISSUE DATE: 8/19/2021** 

Prepared for

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**Testing Laboratory** 

TL-637

### **Revision History**

Rev.	Date	Revisions	Revised By
V1	8/19/2021	Initial Issue	-

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### 1. Attestation of Test Results

Applicant Name	SAMSUNG ELECTRONICS CO., LTD.
FCC ID	A3LSMG780G1
Model Name	SM-G780G/DSM, SM-G780G/DS, SM-G780G
Applicable Standards	FCC 47 CFR § 20.19 ANSI C63.19-2011
HAC Rating	M4
Date Tested	8/17/2021
Test Results	Pass

UL Korea, Ltd. tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL Korea, Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report..

**Note:** This report covers the Samsung model SM-G780G/DSM, SM-G780G/DS and SM-G780G. These models are identical in hardware. Basic model SM-G780G/DS was set for test. See the PED document for details. The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Korea, Ltd. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Korea, Ltd. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by IAS, any agency of the Federal Government, or any agency of any government.

agoney of any government			
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## 2. Test Methodology

The tests documented in this report were performed in accordance with ANSI C63.19-2011 Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids abd FCC Published procedure.

KDB 285076 D01 HAC Guidance v05r01 KDB 285076 D03 HAC FAQ v01r04 TCB workshop updates

#### 3. Facilities and Accreditation

The test sites and measurement facilities used to collect data are located at

Suwon
SAR 2 Room (HAC)

UL Korea, Ltd. is accredited by IAS, Laboratory Code TL-637.

The full scope of accreditation can be viewed at <a href="https://www.iasonline.org/wp-content/uploads/2017/05/TL-637-cert-New.pdf">https://www.iasonline.org/wp-content/uploads/2017/05/TL-637-cert-New.pdf</a>.

# 4. Calibration and Uncertainty

### 4.1. Measuring Instrument Calibration

The measuring equipment utilized to perform the tests documented in this report has been calibrated in accordance with the manufacturer's recommendations, and is traceable to recognized national standards.

Name of Equipment	Manufacturer	Type/Model	Serial No.	Cal. Due Date
MXG Analog Signal Generator	Agilent	N5181A	MY50145882	8-4-2022
Pow er Sensor	Keysight	U2000A	MY60180020	8-4-2022
Pow er Sensor	Agilent	U2000A	MY54260007	8-4-2022
Pow er Amplifier	EXODUS	1410025-AMP2027-10003	10003	8-4-2022
Directional Coupler	Agilent	772D	MY52180193	8-3-2022
Directional Coupler	H.P	778D	16133	8-3-2022
Low Pass Filter	MICROLAB	LA-15N	3943	8-3-2022
Low Pass Filter	FILTRON	L14012FL	1410003S	8-3-2022
Attenuator	Keysight	8491B/010	MY 39272011	8-4-2022
Attenuator	Keysight	8481B/020	MY 39271973	8-4-2022
Attenuator	MINI-CIRCUITS	BW-N3W5+	N/A	8-4-2022
Data Acquisition Electronics (SAR2)	SPEAG	DA E4	1447	3/23/2022
E-Field Probe*	SPEAG	EF3DV3	4064	11/23/2021
Calibration Dipole	SPEAG	CD835V3	1000	9/19/2021
Calibration Dipole	SPEAG	CD1880V3	1000	9/19/2021
Calibration Dipole	SPEAG	CD2600V3	1009	9/17/2021
Radio Communication Tester	R&S	CMW 500	150314	8-3-2022

#### Note(s)

<sup>\*:</sup> According to SPEAG's Technical Report, "MIF Verification", Doc # TR-FB-12.09.04-1, issued date: 9/4/2012. E-field probes are calibrated with specified uncertainty according to ISO 17025 as described in their calibration certificate. The MIF according to the definition in ANSI C63.19 is specific for a modulation and can therefore be used as a constant value if the probe has been PMR calibrated.

### 4.2. Measurement Uncertainty

Measurement Uncertainty for Radio Frequency Emissons Measurement

Error Description	Explanation	Uncertainty value (±%)	Probe Dist.	Divisor	(Ci) E	(Ci) H	Std. Unc.(±%)
Measurement System		· · · · · ·					_
Probe Calibration	A.1	5.10	Normal	1	1	1	5.10
Axial Isotropy	A.2	4.70	Rectangular	1.732	1	1	2.71
Sensor Displacement	A.3	16.50	Rectangular	1.732	1	0.145	9.53
Boundary Effects	A.4	2.40	Rectangular	1.732	1	1	1.39
Phantom Boundary Effects	A.5	7.20	Rectangular	1.732	1	0	4.16
Linearity	A.6	4.70	Rectangular	1.732	1	1	2.71
Scaling to PMR Calibration	A.7	10.00	Rectangular	1.732	1	1	5.77
System Detection Limit	A.8	1.00	Rectangular	1.732	1	1	0.58
Readout Electronics	A.9	0.30	Normal	1	1	1	0.30
Response Time	A.10	0.80	Rectangular	1.732	1	1	0.46
Integration Time	A.11	2.60	Rectangular	1.732	1	1	1.50
RF Ambient Conditions	A.12	3.00	Rectangular	1.732	1	1	1.73
RF Reflections	A.13	12.00	Rectangular	1.732	1	1	6.93
Probe Positioner	A.14	1.20	Rectangular	1.732	1	0.67	0.69
Probe Positioning	A.15	4.70	Rectangular	1.732	1	0.67	2.71
Extrapolation and Interpolation	A.16	1.00	Rectangular	1.732	1	1	0.58
Test sample Related							
Test Positioning Vertical	A.17	4.70	Rectangular	1.732	1	0.67	2.71
Test Positioning Lateral	A.18	1.00	Rectangular	1.732	1	1	0.58
Device Holder and Phantom	A.19	2.40	Rectangular	1.732	1	1	1.39
Power Drift	A.20	5.00	Rectangular	1.732	1	1	2.89
Phantom and Setup Related							
Phantom Thickness	A.21	2.40	Rectangular	1.732	1	0.67	1.39
Combined Std. Uncertainty							16.31
Expanded Std. Uncertainty on Power (Coverage Factor for 95%, k = 2)						32.62	
Expanded Std. Uncertainty on Field							16.31
Notes for table							•

Notes for table

### 4.3. DECISION RULE

Decision rule for statement(s) of conformity is based on Procedure 1, Clause 4.4.2 in IEC Guide 115:2007.

<sup>1.</sup> Ci - is te sensitivity coefficient

<sup>2.</sup> Expanded Std. Uncertainty on Power, Coverage Factor = 2, > 95% Confidence

<sup>3.</sup> Expanded Std. Uncertainty on Field is half value of Expanded Std. Uncertainty on pow er

### 5. System Specifications

E-field measurements are performed using the DASY52 automated dosimetric assessment system. The DASY52 is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland.

The DASY52 HAC Extension consists of the following parts:

#### **Test Arch Phantom**

The specially designed Test Arch allows high precision positioning of both the device and any of the validation dipoles.

#### **EF3DV3 Isotropic E-Field Probe**

Construction: One dipole parallel, two dipoles normal to probe axis

Interleaved sensors

Built-in shielding against static charges

PEEK enclosure material

Calibration: In air from 100 MHz to 3.0 GHz (absolute accuracy ±6.0%, k=2)

ISO/IEC 17025 calibration service available.

Frequency: 40 MHz - > 6 GHz (can be extended to < 20 MHz);

Linearity: ±0.2 dB (100 MHz – 3 GHz)

Directivity:  $\pm 0.2 \text{ dB}$  in air (rotation around probe axis)

± 0.4 dB in air (rotation normal to probe axis)

Dynamic Range: 2 V/m to > 1000 V/m; Linearity: ± 0.2 dB

Dimensions: Overall length: 337 mm (Tip: 20 mm)

Tip diameter: 3.9 mm (Body: 12 mm)

Distance from probe tip to dipole centers: 1.5 mm

Sensor displacement to probe's calibration point: <0.7 mm

Application: General near-field measurements up to 6 GHz

HAC measurements up to 6 GHz Field component measurements Fast automatic scanning in phantoms

## 6. System Validation

The test setup was validated when first configured and verified periodically thereafter to ensure proper function. The procedure provided in this section is a validation procedure using dipole antennas for which the field levels were computed by numeric modeling.

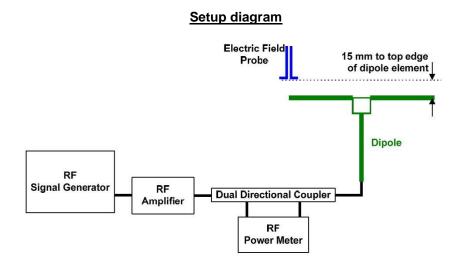
#### Procedure:

Place a dipole antenna meeting the requirements given in ANSI C63.19 in the normally occupied by the WD.

The dipole antenna serves as a known source for an electrical and magnetic output. Position the E-field probe so that the following occurs:

- · The probes and their cables are parallel to the coaxial feed of the dipole antenna
- The probe cables and the coaxial feed of the dipole antenna approach the measurement area from opposite directions
- The center point of the probe element(s) is 15 mm from the closest surface of the dipole elements.

Scan the length of the dipole with the E-field probe and record the two maximum values found near the dipole ends. Average the two readings and compare the reading to the expected value in the calibration certificate or the expected value in this standard.



### 6.1. System Validation Results

SAR			Dipole Cal.	Max. measured from		Average	Target (V/m)	Deviation	Plot
Lab	Date	Dipole Type_Serial #_Freq.	Due Data	above high end (V/m)	above low end (V/m)	max. above arm (V/m)	(From SPEAG)	(note 1) ± %	No.
SAR 2	08-17-2021	CD835V3_SN:1000_(835MHz)	09-19-2021	114.60	109.10	111.85	105.90	5.62	1
SAR 2	08-17-2021	CD1880V3_SN:1000_(1880MHz)	09-19-2021	93.50	91.41	92.46	85.70	7.88	2
SAR 2	08-17-2021	CD2600V3_SN:1009_(2600MHz)	09-17-2021	92.39	89.28	90.84	84.30	7.75	3

#### **Notes**

- 1) Delta (Deviation) % = 100 \* (Measured value minus Target value) divided by the Target value. Deltas within ±25% are acceptable, of which 12% is deviation and 13% is measurement uncertainty.
- The maximum E-field or were evaluated and compared to the target values provided by SPEAG in the calibration certificate of specific dipoles.
- 3) Please refer to the appendix for detailed measurement data and plots.

# 7. Average Antenna Input Power & Evaluation for Low-power Exemption

An RF air interface technology of a device is exempt from testing when its average antenna input power plus its **MIF** is ≤17 dBm for any of its operating modes. If a device supports multiple RF air interfaces, each RF air interface shall be evaluated individually.

Air-Interface	Average Antenna Input Power (dBm) <sup>1</sup>	Worst Case MIF (dB)	Input Power plus its MIF (dBm)	HAC Tested
GSM850	34.0	3.63	37.63	Yes
GSM1900	31.0	3.63	34.63	Yes
W-CDMA Band II	24.0	-27.23	-3.23	No
W-CDMA Band IV	24.0	-27.23	-3.23	No
W-CDMA Band V	25.8	-27.23	-1.43	No
LTE Band 2	24.0	-9.76	14.24	No
LTE Band 4	24.0	-9.76	14.24	No
LTE Band 5	25.8	-9.76	16.04	No
LTE Band 12	24.0	-9.76	14.24	No
LTE Band 13	24.0	-9.76	14.24	No
LTE Band 17	24.0	-9.76	14.24	No
LTE Band 26	23.5	-9.76	13.74	No
LTE Band 66	24.0	-9.76	14.24	No
LTE Band 41	25.0	-1.44	23.56	Yes
802.11b Antenna 1	13.0	-2.02	10.98	No
802.11g Antenna 1	13.0	0.12	13.12	No
802.11a Antenna 1	11.0	-3.15	7.85	No
802.11ax Antenna 1	13.0	-5.58	7.42	No
802.11b Antenna 2	13.0	-2.02	10.98	No
802.11g Antenna 2	13.0	0.12	13.12	No
802.11a Antenna 2	11.0	-3.15	7.85	No
802.11ax Antenna 2	13.0	-5.58	7.42	No

#### Note(s):

- 1. Max tune-up limit.
- 2. WLAN supports power reduction during voice call.

# 8. Device Under Test

Normal operation	Held to head				
Back Cover	The Back Cover is not removable				
	S/N	Notes			
Test sample information	R38R301JR2K	RF Emission Test			

# 8.1. Air Interfaces and Operating Mode

Air Interface	Bands (MHz)	Type	C63.19 Tested	Simultaneous Transmitter	OTT Testing Required? Name of Voice Service	Pow er Reduction
	850	VO	Yes	Wi-Fi and BT	CMRS	NA
GSM	1900	VO res		WHITAIIQ BI	CIVIIAS	No
<b>33</b>	GPRS/EDGE	VD	No	Wi-Fi and BT	Google Duo	NA
	850 (V)					
W-CDMA (UMTS)	1750 (IV)	VO	No <sup>1</sup>	Wi-Fi and BT	CMRS	NA
	1900 (II)					
(= = -,	HSPA	VD	No <sup>1</sup>	Wi-Fi and BT	Google Duo	NA
	700 (B12/13/17)	VD	No <sup>1</sup>	Wi-Fi and BT	VoLTE Google Duo	NA
LTE - FDD	850 (B5/26)					
LIE-FUU	1700 (B4/66)					
	1900 (B2)					
LTE - TDD	2600 (B41)	VD	Yes	Wi-Fi and BT	VoLTE Google Duo	NA
	2450			WWAN, Wi-Fi 5 GHz and BT		
\\/; F;	5200 (U-NII-1)	VD	No <sup>1</sup>		VoWi-Fi	NA
Wi-Fi	5300 (U-NII-2A)	۷۵	INO	WWAN,	Google Duo	INA
	5500 (U-NII-2C)			Wi-Fi 2.4 GHz and BT		
	5800 (U-NII-3)					
BT	2450	DT	NA	WWAN and Wi-Fi	NA	NA

Type Note:

VO: Legacy Cellular Voice Service

DT: Digital Transport only (no voice)

VD: IP Voice Service over Digital Transport

CMRS: Commercial Mobile Radio Service

BT: Bluetooth

1. Evaluated for MIF and low power exemption

# 9. Modulation Interference Factor (MIF)

The HAC Standard ANSI C63.19 defines a new scaling using the Modulation Interference Factor (MIF) which replaces the need for the Articulation Weighting Factor (AWF) during the evaluation and is applicable to any modulation scheme.

The Modulation Interference factor (MIF, in dB) is added to the measured average E-field (in dBV/m) and converts it to the RF Audio Interference level (in dBV/m). This level considers the audible amplitude modulation components in the RF E-field. CW fields without amplitude modulation are assumed to not interfere with the hearing aid electronics. Modulations without time slots and low fluctuations at low frequencies have low MIF values, TDMA modulations with narrow transmission and repetition rates of few 100 Hz have high MIF values and give similar classifications as ANSI C63.19.

#### **Definitions**

E-field probes have a bandwidth <10 kHz and can therefore not evaluate the RF envelope in the full audio band. DASY52 is therefore using the "indirect" measurement method according to ANSI C63.19 which is the primary method. These near field probes read the averaged E-field measurement. Especially for the new high peak-to-average (PAR) signal types, the probes shall be linearized by probe modulation response (PMR) calibration in order to not overestimate the field reading.

The evaluation method or the MIF is defined in ANSI C63.19 section D.7. An RMS demodulated RF signal is fed to a spectral filter (similar to an A weighting filter) and forwarded to a temporal filter acting as a quasi-peak detector. The averaged output of these filtering is called to a 1 kHz 80% AM signal as reference. MIF measurement requires additional instrumentation and is not well suited for evaluation by the end user with reasonable uncertainty It may alternatively be determined through analysis and simulation, because it is constraint and characteristic for a communication signal. DASY52 uses well defined signals for PMR calibration. The MIF of these signals has been determined by simulation and is automatically applied.

MIF values were not tested by a probe or as specified in the standards but are based on analysis provided by SPEAG for all the air interfaces (GSM, WCDMA, LTE, and Wi-Fi). The data included in this report are for the worst case operating modes. The UIDs used are listed below:

UID	Communication System Name	MIF (dB)
10021-DAC	GSM-FDD (TDMA, GMSK)	3.63
10011-CAB	UMTS-FDD (WCDMA)	-27.23
10170-CAE	LTE-FDD (SC-FDMA, 1 RB, 20 MHz, 16QAM)	-9.76
10182-CAE	LTE-FDD (SC-FDMA, 1 RB, 15 MHz, 16QAM)	-9.76
10176-CAF	LTE-FDD (SC-FDMA, 1 RB, 10 MHz, 16QAM)	-9.76
10173-CAG	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16QAM)	-1.44
10061-CAB	IEEE 802.11b WiFi 2.4 GHz (DSSS, 11 Mbps)	-2.02
10077-CAB	IEEE 802.11g WiFi 2.4 GHz (DSSS/OFDM, 54 Mbps)	0.12
10069-CAC	IEEE 802.11a/h WiFi 5 GHz (OFDM, 54 Mbps)	-3.15
10671-AAA	IEEE 802.11ax (20MHz, MCS 0 90pc duty cycle)	-5.58

A PMR calibrated probe is linearized for the selected waveform over the full dynamic range within the uncertainty specified in its calibration certificate. E-field probes have a bandwidth <10 kHz and can therefore not evaluate the RF envelope in the full audio band. DASY52 is therefore using the \indirect" measurement method according to ANSI C63.19 which is the primary method. These near field probes read the averaged E-field measurement. Especially for the new high peak-to-average (PAR) signal types, the probes shall be linearized by PMR calibration in order to not overestimate the field reading.

The MIF measurement uncertainty is estimated as follows, for modulation frequencies from slotted waveforms with fundamental frequency and at least 2 harmonics within 10 kHz:

- 0.2 dB for MIF -7 to +5 dB.
- 0.5 dB for MIF -13 to +11 dB
- 1 dB for MIF > -20 dB

### 10. HAC RF Emissions Test Procedure

The following are step-by-step test procedures.

- a) Confirm proper operation of the field probe, probe measurement system and other instrumentation and the positioning system.
- b) Position the WD in its intended test position.
- c) Set the WD to transmit a fixed and repeatable combination of signal power and modulation characteristic that is representative of the worst case (highest interference potential) encountered in normal use. Transiently occurring start-up, changeover, or termination conditions, or other operations likely to occur less than 1% of the time during normal operation, may be excluded from consideration.
- d) The center sub-grid shall be centered on the T-Coil mode perpendicular measurement point or the acoustic output, as appropriate. Locate the field probe at the initial test position in the 50 mm by 50 mm grid, which is contained in the measurement plane, refer to illustrated in Figure 1. If the field alignment method is used, align the probe for maximum field reception.
- e) Record the reading at the output of the measurement system
- f) Scan the entire 50 mm by 50 mm region in equally spaced increments and record the reading at each measurement point. The distance between measurement points shall be sufficient to assure the identification of the maximum reading.
- g) Identify the five contiguous sub-grids around the center sub-grid whose maximum reading is the lowest of all available choices. This eliminates the three sub-grids with the maximum readings. Thus, the six areas to be used to determine the WD's highest emissions are identified.
- h) Identify the maximum reading within the non-excluded sub-grids identified in step g).
- Convert the highest field reading within identified in step h) to RF audio interference level, in V/m, by taking the square root of the reading and then dividing it by the measurement system transfer function, established in 5.5.1.1 Convert this result to dB(V/m) by taking the base-10 logarithm and multiplying by 20.
  - Indirect measurement method
  - Replacing step i), the RF audio interference level in dB (V/m) is obtained by adding the MIF (in dB) to the maximum steady-state rms field-strength reading, in dB (V/m), from step h). Use this result to determine the category rating
- j) Compare this RF audio interference level with the categories in Clause 8 (ANSI C63.19) and record the resulting WD category rating
- k) For the T-Coil mode M-rating assessment, determine whether the chosen perpendicular measurement point is contained in an included sub-grid of the first scan. If so, then a second scan is not necessary. The first scan and resultant category rating may be used for the T-Coil mode M rating.
  - Otherwise, repeat step a) through step i), with the grid shifted so that it is centered on the perpendicular measurement point. Record the WD category rating.

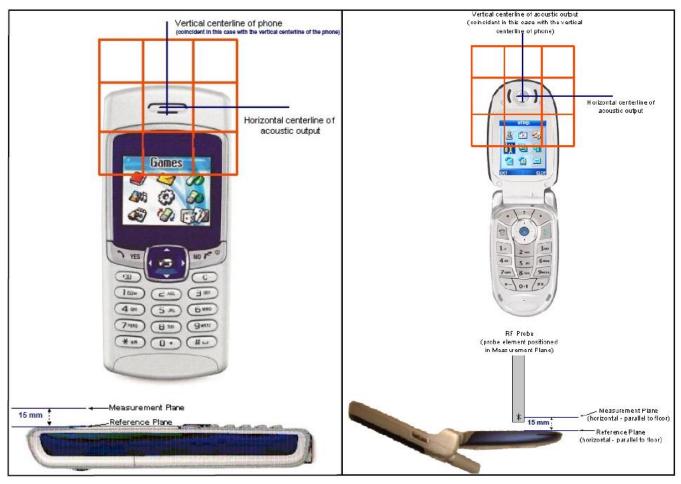


Figure 1 - WD reference and plane for RF emission measurements

#### Test flowchart Per ANSI-63.19-2011

- Confirm proper operation of probes and instrumentation
- > Position WD
- > Configure WD TX operation

Per 5.4.1.2 (1-3)

- Initialize field probe
- Scan Area

Per 5.4.1.2 (4-6)

- Identify exclusion area.
- Resean or reanalyze open area to determine maximum
- Direct method: Record RF Audio Interference Level, in dB(V/m)
- Indirect method: Add the MIF to the maximum steady state rms field strength and record RF Audio Interference Level, in dB(V/m)

Per 5.4.1.2 (7-9) & 5.4.1.3

Identify and record the category

Per 5.4.1.2 (9-10)

### 11. RF Emissions Measurement Criteria

WD RF audio interference level caterories in logarithmic units

	E-field emissions			
Emission Categories	< 960 MHz	> 960 MHz		
Category M1	50 to 55 dB (V/m)	40 to 45 dB (V/m)		
Category M2	45 to 50 dB (V/m)	35 to 40 dB (V/m)		
Category M3	40 to 45 dB (V/m)	30 to 35 dB (V/m)		
Category M4	<40 dB (V/m)	<30 dB (V/m)		

# 12. HAC (RF Emissions) Test Results

MIF values were not tested by a probe or as specified in the standards but are based on analysis provided by SPEAG for the following User Identifiers and air interfaces.

The data included in this report are for the worst case operating modes. Refer to Appendix D and G for the MIF vales that represent the worst case operation modes.

Air-Interface	Ch. No.	Freq. (MHz)	Results* (dB V/m)	Results plus 0.2dB uncertaninty (dB V/m)	Margin (dB)	M-Rating	Plots Page #
GSM850	128	824.2	33.71	33.91	6.09	M4	1
	190	836.6	33.25	33.45	6.55	M4	2
	251	848.6	31.91	32.11	7.89	M4	3
GSM1900	512	1850.2	24.44	24.64	5.36	M4	4
	661	1880.0	24.38	24.58	5.42	M4	5
	810	1909.8	24.46	24.66	5.34	M4	6
LTE-TDD Band 41	39750	2506.0	19.26	19.46	10.54	M4	7
	40185	2549.5	20.07	20.27	9.73	M4	8
	40620	2593.0	19.89	20.09	9.91	M4	9
	41055	2636.5	17.90	18.10	11.90	M4	10
	41490	2680.0	17.49	17.69	12.31	M4	11
W-CDMA & LTE-FDD & Wi-Fi	Refer to Section 7 Evaluation for Low-power Exemption. RF Emission testing for this device is required only for GSM voice modes and LTE-TDD. All other applicable air-interfaces are exempt from testing in accordance with C63.19 Clause 4.4 and are rated M4.					M4	N/A

#### Note(s):

<sup>\*:</sup> Measured Audio Interference level in dB (V/m): indirect method (max rms field strength Plus MIF)

Date: 2021-08-17

#### 12.1. Worst Case RF Emission Test Plot

Test Laboratory: UL Korea Ltd. Suwon Laboratory

#### **GSM 1900**

Communication System: UID 10021 - DAC, GSM-FDD (TDMA, GMSK); Frequency: 1909.8 MHz; Duty Cycle: 1:8.6896 Phantom section: TCoil Section

DASY5 Configuration:

- Probe: EF3DV3 SN4064; ConvF(1, 1, 1) @ 1909.8 MHz; Calibrated: 2020-11-23
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1447; Calibrated: 2021-03-23
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BB
- Measurement SW: DASY52, Version 52.10 (4);SEMCAD X Version 14.6.14 (7483)

### GSM1900 E-Field measurement/Voice\_ch810/Hearing Aid Compatibility Test

(101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 10.87 V/m; Power Drift = 0.08 dB

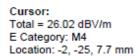
Applied MIF = 3.63 dB

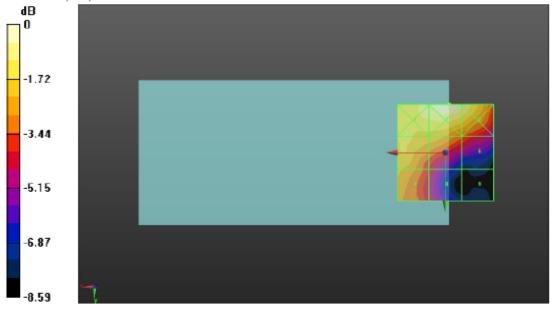
RF audio interference level = 24.46 dBV/m

Emission category: M4

#### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
25,35 dBV/m	26.02 dBV/m	25,55 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
24.46 dBV/m	24.08 dBV/m	22.78 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
23,91 dBV/m	22.03 dBV/m	18.73 dBV/m





0 dB = 20.00 V/m = 26.02 dBV/m

### **Appendixes**

Refer to separated files for the following appendixes

4790047196-S2 Appendix A: Setup Photo

4790047196-S2 Appendix B: System Validation Plots

4790047196-S2 Appendix C: Test Plots

4790047196-S2 Appendix D: MIF Attestation Letter

4790047196-S2 Appendix E: Probe Certificates

4790047196-S2 Appendix F: Dipole Certificates

4790047196-S2 Appendix G: UID Specifications

**END OF REPORT**